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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Eran Dvir, Eli Haimovich, and Benjamin Shulman
Assignee: Nova Measuring Instruments, Ltd.
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING POLISHING
Serial No.: 08/497,382 Filed: June 29, 1995
Examiner: E. Morgan Group Art Unit: 3203
Batch No.: U26 Allowed: November 17, 1997
Docket No.: M-3417 US

San Jose, California
February 17, 1998

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COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D. C. 20231

**REQUEST TO AMEND DRAWINGS
UNDER 37 C.F.R. § 1.123**

Sir:

Pursuant to 37 C.F.R. §1.123, Applicants respectfully request permission to amend Figs. 6, 7, 8, and 9 as shown in red on the accompanying sheets. Formal drawings incorporating the requested amendments are submitted herewith.

Should the Examiner have any questions concerning this request, the Examiner is invited to call the undersigned at (408) 453-9200.

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231,

on February 17, 1998.

David W. Heid

Attorney for Applicant(s)

17 Feb 98

Date of Signature

Respectfully submitted,

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